


<b>Search Notes</b>  	<b>Application/Control No.</b>  10617027	<b>Applicant(s)/Patent Under Reexamination</b>  KIM ET AL.
	<b>Examiner</b>  Chawan, Sheela C	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	181,190,100,191,207,214,106,107,128,130-134,254,255,263,264,276,280,277	5/23/07	SCC
600	463,462,437,461,448,455,459,467,458,443,444,445,446,447	"	"
128	916,925,915	"	"
73	642	"	"
424	9.52,9.5,602,9.42,9.51,600	"	"
977	904,929	"	"
ABOVE SEARCH UP-DATE		"	"

SEARCH NOTES		
Search Notes	Date	Examiner
SEARCH EAST AND OTHER DATABASE., SEE ATTACHED SEARCH HISTORY.	5/23/07	SCC
382/100,128,130- 134,280.CCLS. US- PATENT ONLY , SEE TEXT SEARCH.	"	"
600/463,443,462,437,461,448,455.CCLS.	"	"
"	"	"
424/9.52, 9.5, 602,9.42, 9.51.CCLS.	"	"
"	"	"
INVENTOR NAME SEARCH.	"	"
INTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT.	"	"
SEARCH IEEE OR INSPEC DATABASE.	"	"
ABOVE SEARCH UP-DATE.	"	"

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	128,181,280	5/23/07	SCC
600	437,443,463	"	"
128	916	"	"